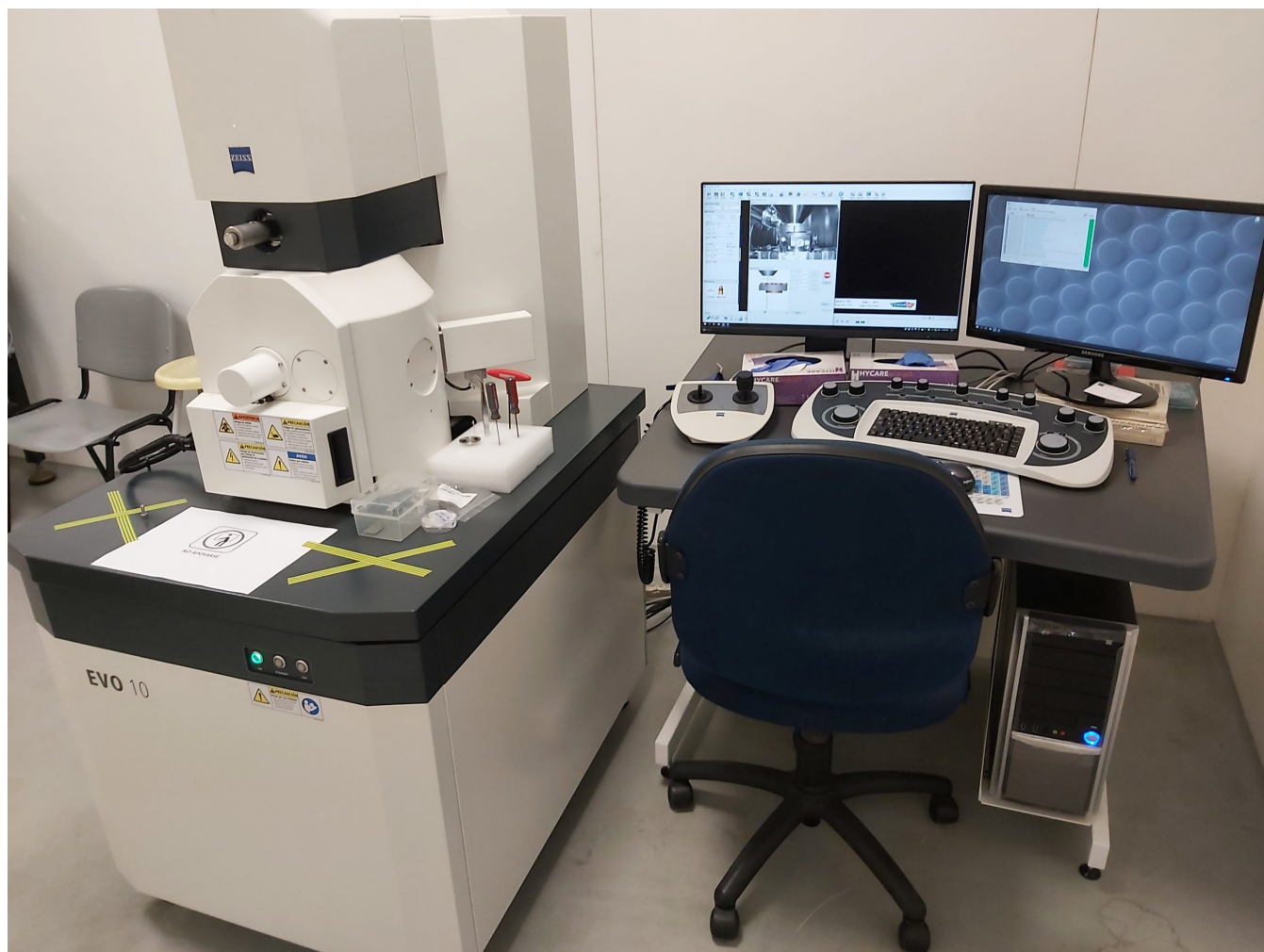


# Electron microscopy service

Structural analysis of samples of different sizes. Conductive and insulating samples are analysed. Metal coating for insulating samples can be requested as an add-on.



## Contact information

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## Technological Offers type

Technological scientific services

## Research and innovation areas

- Science For Engineering and Architecture

## ODS



**Available from:** 2021

## **Where?**

Centre of Advanced Materials and Devices for Information and Communications Technology (CEMDATIC)

Keywords: | [electron microscopy](#) | [SEM](#)

## **Electron microscopy service**

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### **Description of the services offered**

Analysis of micrometric and nanometric structures in samples of various sizes. Conductive and insulating samples can be analysed. Metal coating can also be requested for insulating samples. The service may be used individually after training with the equipment.

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### **Needs requested and applications**

Analysis of conductive and insulating nano and micrometric structures.

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### **Sector or area of application**

Nanotechnology, Microtechnology.

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### **Equipment description**

CEMDATIC, HTSE for Telecommunications

A Zeiss EVO scanning electron microscope is used to give this service, which enables detection of backscattered and secondary electrons; variable continuous acceleration voltage between 0.02 kV and 30 kV in 10V steps; 8.5 mm analytical working distance; currents from 0.5 pA up to 5 uA; 5 axis motorised base: X, Y, Z, tilt up to 90° and 360° rotation; 310 mm internal diameter and 220 mm high sample chamber; image scanner up to 32k x 24k pixels.

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### **Request for service**

Request the service by e-mail to [cemdatic@upm.es](mailto:cemdatic@upm.es) indicating preferred dates and experience in using scanning electron microscopes.